

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 35.C13314 DII		APPLICATION NO. DIV. OF U.S. A.N. 09/848,360		
			APPLICANT TOSHIKAZU ONISHI ET AL.				
			FILING DATE FILED HEREWITH		GROUP 2879		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
KJN	6,005,333	12/99	Kaneko et al.	313	306		
KJN	6,313,815	11/01	Takeda et al.	345	75.2		
KJN	6,309,272	10/01	Nishimura	445	25		
KJN	6,169,356 B1	1/01	Ohnishi et al.	313	495		
KJN	6,184,610 B1	2/01	Shibata et al.	313	309		
KJN	4,904,895	2/90	Tsukamoto et al.	313	336		
KJN	5,749,763	5/98	Yoshioka et al.	445	51		
KJN	5,605,483	2/97	Takeda et al.	445	2		
KJN	5,719,027	2/98	Miyazaki et al.	435	6		
KJN	5,735,920	4/98	Omori et al.	65	29.18		
KJN	5,066,883	11/91	Yoshioka et al.	313	309		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLAS	TRANSLATION YES/NO/ OR ABSTRACT	
KJN	0 660 357 A1	6/28/95	EPO			English	
KJN	8-334124	12/13/96	JAPAN			Yes	
KJN	8-7749	1/12/96	JAPAN			Yes	
KJN	9-237571	9/9/97	JAPAN			No	
KJN	0 805 472 A1	11/97	EPO			English	
KJN	64-31332	2/89	JAPAN			Abstract	
EXAMINER			DATE CONSIDERED				

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Sheet 1 of 2

KENNETH J. RAMSEY
PRIMARY EXAMINER

1/28/03

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APPLICANT

TOSHIKAZU ONISHI ET AL.

FILING DATE

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
K/H	5,591,061	1/97	Ikeda et al.	445	6	
K/H	5,853,310	12/98	Nishimura et al.	445	24	
K/H	6,221,426	4/01	Yamanobe	427	77	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

K/H	W.P. Dyke, et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. VIII, pp. 89-185, 1956
K/H	C.A. Spindt et al., "Physical properties of thin-film field emission cathodes with molybdenum cones", J. Appl. Phys., Vol. 47, No. 12, pp. 5248-5263, 1976.
K/H	C.A. Mead, "Operation of Tunnel-Emission Devices", J. Appl. Phys., Vol. 32, No. 4, pp. 646-652, 1961.
K/H	M.L. Elinson, "The emission of hot electrons and the field emission of electrons from tin oxide", Radio Engineering and Electron Physics, pp. 1290-1296, 1965.
K/H	"Experimental Physics Lesson 14, Surface and Fine Grains", (ed., Koreo Kinoshita, Kyoritsu Shuppan, published on September 1, 1986).
K/H	"Ultra Fine Particles - Creative-science and technology", (ed., Chikara Hayashi, Ryoji Ueda, and Akira Tasaki, Mita Shuppan, published 1988).

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